

# Oct 9 presentation

## Summary of divergence metrics used in domain adaptation

## $\mathcal{A}$ -distance and implied $\mathcal{H}$ -distance (Ben-David et al., 2006)

Let  $\mathcal{A}$  be a family of subsets of  $\mathcal{X}$ . The  $\mathcal{A}$ -distance between two distributions  $\mathcal{D}$  and  $\mathcal{D}'$  is defined as

$$d_{\mathcal{A}}(\mathcal{D}, \mathcal{D}') = 2 \sup_{A \in \mathcal{A}} |\Pr_{\mathcal{D}}[A] - \Pr_{\mathcal{D}'}[A]|$$

For a binary function class  $\mathcal{H}$  we will define  $\mathcal{H}$ -distance, denoted as  $d_{\mathcal{H}}(\cdot, \cdot)$ , to indicate the  $\mathcal{A}$ -distance on the class of subsets whose indicator functions are in  $\mathcal{H}$ ,

$$d_{\mathcal{H}}(\mathcal{D}, \mathcal{D}') = 2 \sup_{A: 1_A \in \mathcal{H}} |\Pr_{\mathcal{D}}[A] - \Pr_{\mathcal{D}'}[A]|$$

- The distance was used to derive a generalization bound for domain adaptation. The key ingredient in the bound is  $d_{\mathcal{H}}(\tilde{\mathcal{D}}_S, \tilde{\mathcal{D}}_T)$

## KL divergence (Liu et al., 2014; Chen et al., 2016, etc.)

For two distributions  $P$  and  $Q$  defined on the same probability space, with  $P$  absolutely continuous with respect to  $Q$ , i.e.,  $P$  is dominated by  $Q$ , the KL divergence is defined as

$$D_{KL}(P\|Q) = \int \log\left(\frac{dP}{dQ}\right) dP$$

The KL divergence was used in the Robust bias-aware (RBA) probabilistic classifier (Liu et al., 2014) and the Robust Covariate Shift Regression (Chen et al., 2016).

The log-loss the author defined is as follows:

$$\text{logloss}_{P_{\text{ug}}(X)}(P(Y | X), \hat{P}(Y | X)) \triangleq \mathbb{E}_{P_{\text{ug}}(x)P(y|x)}[-\log \hat{P}(Y | X)],$$

## Rényi divergence (Mansour et al., 2009)

Rényi Divergence which is parameterized by  $\alpha$  is defined by

$$D_\alpha(P\|Q) = \frac{1}{\alpha - 1} \log \sum_x P(x) \left( \frac{P(x)}{Q(x)} \right)^{\alpha-1}.$$

- For  $\alpha = 1$ ,  $D_1(P\|Q)$  coincides with the standard relative entropy or KL-divergence.
- For  $\alpha = 2$ ,  $D_2(P\|Q) = \log \mathbb{E}_{x \sim P} \frac{P(x)}{Q(x)}$  is the logarithm of the expected probabilities ratio.
- For  $\alpha = \infty$ ,  $D_\infty(P\|Q) = \log \sup_{x \in \mathcal{X}} \frac{P(x)}{Q(x)}$ , which bounds the maximum ratio between the two probability distributions.

The authors usually denote by  $d_\alpha(P\|Q)$  the exponential in base 2 of the Rényi divergence:

$$d_\alpha(P\|Q) = 2^{D_\alpha(P\|Q)} = \left[ \sum_x \frac{P^\alpha(x)}{Q^{\alpha-1}(x)} \right]^{\frac{1}{\alpha-1}}.$$

A key lemma in the paper is the following:

**Lemma 1** For any distributions  $P$  and  $Q$ , functions  $f$  and  $h$  and loss  $L$  and  $\alpha > 1$ , the following inequalities hold:

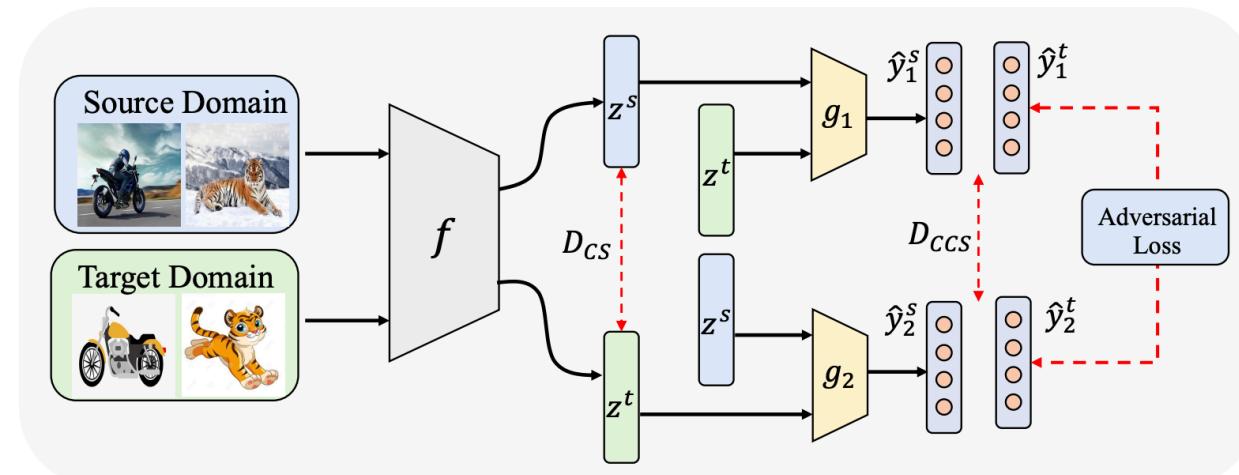
$$\begin{aligned} \mathcal{L}_P(h, f) &\leq (d_\alpha(P\|Q) E_{x \sim Q} [L^{\frac{\alpha}{\alpha-1}}(h(x), f(x))])^{\frac{\alpha-1}{\alpha}} \\ &\leq (d_\alpha(P\|Q) \mathcal{L}_Q(h, f))^{\frac{\alpha-1}{\alpha}} M^{\frac{1}{\alpha}} \end{aligned}$$

The lemma bounds the loss of a hypothesis  $h$  with respect to a distribution  $P$  in terms of the loss of  $h$  to another distribution  $Q$  and the Rényi divergence between  $P$  and  $Q$ .

# Feature alignment and Adversarial training (Tzeng et al., 2014; Long et al., 2015; Ganin et al., 2016, etc.)

Feature alignment methods try to learn a feature representation such that the source and target distributions are close in the new feature space.

This requires a distance metric to measure the distance between the two distributions in the feature space.



The distance metrics used in these papers include Maximum Mean Discrepancy (MMD) (Tzeng et al., 2014; Long et al., 2015) and domain classifier loss (Ganin et al., 2016), Wasserstein distance (Courty et al., 2017), Jensen-Shannon divergence (Shui et al., 2022), Cauchy-Schwarz (CS) divergence (Yin et al., 2024), Stein discrepancy (Seeger et al., 2025).

## Maximum Mean Discrepancy (Tzeng et al., 2014; Long et al., 2015)

The MMD between two distributions  $P$  and  $Q$  is defined as

$$\text{MMD}(P, Q) = \sup_{\|f\|_{\mathcal{H}} \leq 1} (\mathbb{E}_{x \sim P}[f(x)] - \mathbb{E}_{x \sim Q}[f(x)])$$

where  $\mathcal{H}$  is a reproducing kernel Hilbert space (RKHS).

## Cauchy-Schwarz divergence (Yin et al., 2024)

Cauchy-Schwarz Divergence Motivated by the wellknown Cauchy-Schwarz (CS) inequality for squareintegrable functions:

$$\left( \int p(\mathbf{x})q(\mathbf{x})d\mathbf{x} \right)^2 \leq \int p(\mathbf{x})^2 d\mathbf{x} \int q(\mathbf{x})^2 d\mathbf{x},$$

with equality if and only if  $p(\mathbf{x})$  and  $q(\mathbf{x})$  are linearly dependent, the CS divergence [Principle et al., 2000a,b] defines the distance between probability density functions by measuring the tightness (or gap) of the left-hand side and right-hand side of Eq. (1) using the logarithm of their ratio:

$$D_{\text{CS}}(p; q) = -\log \left( \frac{\left( \int p(\mathbf{x})q(\mathbf{x})d\mathbf{x} \right)^2}{\int p(\mathbf{x})^2 d\mathbf{x} \int q(\mathbf{x})^2 d\mathbf{x}} \right).$$

## Wasserstein distance (Courty et al., 2017)

The Wasserstein distance between two distributions  $P$  and  $Q$  is defined as

$$W(P, Q) = \inf_{\gamma \in \Pi(P, Q)} \int_{\mathcal{X} \times \mathcal{X}} c(x, y) d\gamma(x, y)$$

where  $\Pi(P, Q)$  is the set of all joint distributions  $\gamma(x, y)$  whose marginals are  $P$  and  $Q$ , and  $c(x, y)$  is a cost function.

- The Wasserstein distance can be viewed as the minimum cost of transporting mass in transforming the distribution  $P$  into  $Q$ .

## Jensen-Shannon divergence (Shui et al., 2022)

The Jensen-Shannon (JS) divergence between two distributions  $P$  and  $Q$  is defined as

$$D_{\text{JS}}(P\|Q) = \frac{1}{2}(D_{\text{KL}}(P\|M) + D_{\text{KL}}(Q\|M))$$

where  $M = \frac{1}{2}(P + Q)$  is the mixture distribution of  $P$  and  $Q$ , and  $D_{\text{KL}}$  is the KL divergence

- The JS divergence is a symmetrized and smoothed version of the KL divergence.

## Stein discrepancy (Seeger et al., 2025)

The Stein discrepancy between two distributions  $P$  and  $Q$  is defined as

$$D_{\text{Stein}}(P\|Q) = \sup_{f \in \mathcal{F}} |\mathbb{E}_{x \sim P}[\mathcal{A}_Q f(x)]|$$

where  $\mathcal{A}_Q$  is the Stein operator associated with  $Q$ , and  $\mathcal{F}$  is a class of test functions.

Stein operator is defined as

$$\mathcal{A}_Q f(x) = \nabla_x \log q(x) f(x) + \nabla_x f(x)$$

- The Stein discrepancy tests whether  $q$  behaves like  $p$  using “smart probes”  $f$ .
- The Stein discrepancy is zero if and only if  $P = Q$ .